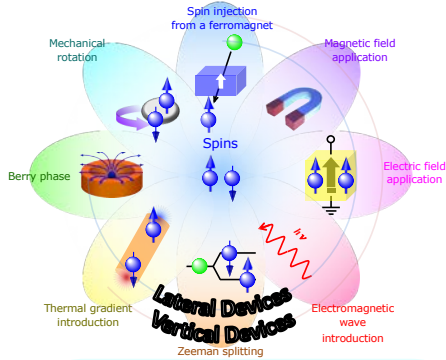


Current-Induced Crystallisation in Heusler Alloy Films

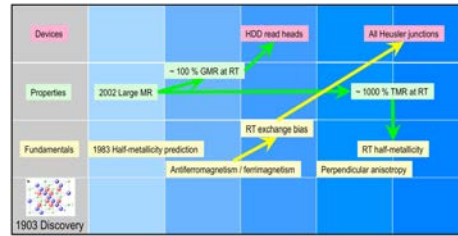
W. Frost,¹ K. Elphick,¹ M. Samiepour¹ and A. Hirohata¹

¹Department of Electronic Engineering, University of York, York YO10 5DD, United Kingdom

Spin Generation^[1]

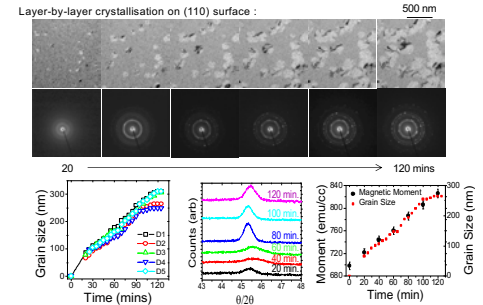


Roadmap on Heusler Alloys^[2]



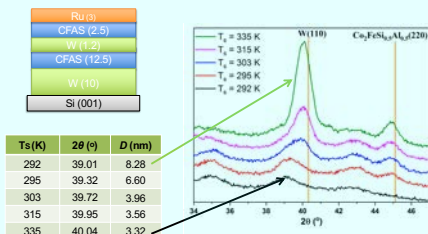
[1] A. Hirohata et al., *J. Magn. Magn. Mater.* **509**, 166711 (2020).
[2] A. Hirohata et al., *IEEE Trans. Magn.* **51**, 07160747 (2015).
[3] J. Sagar et al., *Appl. Phys. Lett.* **105**, 032401 (2014).

Low-Temperature Crystallisation^[3]



Low-Temperature Deposition

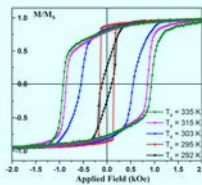
Co₂FeAl_{0.5}Si_{0.5} (CFAS)/W/CFAS trilayers were sputtered at substrate temperatures T_s :



Magnetic Properties

CFAS/W/CFAS trilayers : *

- Low T_s film has strong intergranular exchange coupling.
- This gives a highly square, low H_c loop.
- Higher T_s → 50% of the reversal is via domain rotation.
- The remainder is via nucleation and domain wall pinning.

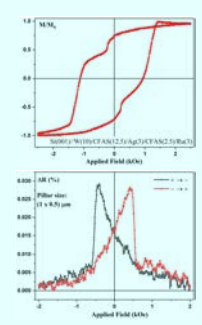


→ The is similar to CoFe and would be suitable for a GMR device.

Device Characterisation

CFAS/Ag/CFAS nanopillars fabricated :

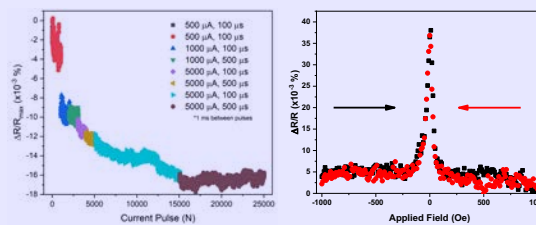
- Due to the lack of individual layer switching in multilayers using a W spacer, Ag was used.
- A 3 nm layer of Ag provided a loop with two distinct switches dependent on layer thickness.
- A small GMR of 0.025% was observed perpendicular-to-plane for device of $(1 \times 0.5) \mu\text{m}^2$.
- Switching occurs at the same field as in the $M-H$ loop, confirming layer thickness dependent switching.



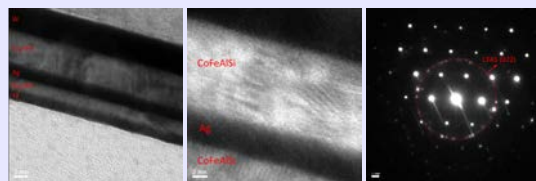
[4] A. Hirohata et al., *Materials*, **11**, 105 (2018).

Current-Induced Crystallisation

CFAS/Ag/CFAS nanopillars :

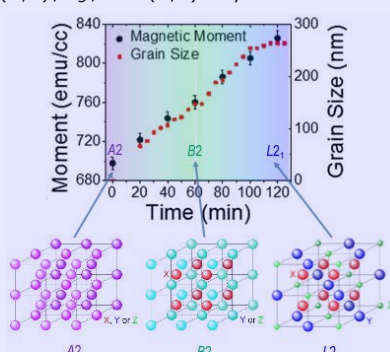


High-resolution transmission electron micrographs :



- Cross-sectional TEM images of the GMR device with 300k and 800k magnification.
- Diffraction pattern confirms CFAS (220) crystallisation.
- Lattice constant is estimated to be 0.57 nm, which is 96.6% of that estimated by the corresponding XRD.

Co₂Fe(Al,Si) / Ag / Co₂Fe(Al,Si) trilayers : *



- The current-induced crystallisation leads to the reduction in the corresponding resistivity.
- This acts as memory potentiation for an artificial GMR synapse.
- This offers more realistic neuromorphic computation with higher efficiency.

Summary

- The concept of the **current-induced crystallisation** has been successfully demonstrated in a Heusler-alloy GMR junction.
- Due to the nature of a simple electrical current introduction, a nanoelectronics device does **not require annealing processes but stores the operation cycle permanently**.
- The current-induced crystallisation minimises any atomic diffusion and interfacial mixing to degrade their performance.
- The current-induced crystallisation is expected to be used in a variety of nanoelectronics devices, including a neuromorphic node network.